

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	HIGH-PRESSURE PROCESSING CHAMBER FOR A SEMICONDUCTOR WAFER																						
Application Number :	10/680783																						
Confirmation Number:	5859																						
First Named Applicant:	William Jones																						
Attorney Docket Number:																							
Art Unit:																							
Examiner:																							
Search string:	(20030051741).pn																						
<p><u>Certification:</u> This Information Disclosure Statement was submitted under the following conditions, which satisfies the requirement under 37 CFR 1.97(e). The filer certified:</p> <p>That no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR 1.56(c) more than three months prior to the filing of the information disclosure statement.</p>																							
<h3>US Published Applications</h3> <p>Note: Applicant is not required to submit a paper copy of cited US Published Applications</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Pub. No.</th><th>Date</th><th>Applicant</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>20030051741</td><td>2003-03-20</td><td>DeSimone et al.</td><td></td><td></td><td></td></tr></tbody></table>								init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass		1	20030051741	2003-03-20	DeSimone et al.			
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